

METHOD AND SYSTEM FOR COMPARING DIFFERENT
INTEGRATED CIRCUIT TECHNOLOGIES

ABSTRACT

The present invention is directed to a method and system for comparing different IC technologies. According to an exemplary aspect of the present invention, an interactive computer program takes a multidimensional space represented by all of the variability associated with design and production of complex semiconductor devices, and collapses it down into a smaller space representing key variables of interest, and particularly the key variables of interest to a customer such as risk and cost. Sliders may be used by a customer to set input variables reflecting realistic requirements on the part of the customer. For output, 3-D and/or 2-D graphics may be used to show how the IC technologies visually line up in relation to one another in terms of risk and also in terms of cost.